IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants:	Takahiro Yamaguchi, et al.		
Serial No.:	09/813,923	Examiner:	Khai Tran
Filing Date:	March 20, 2001	Art Unit:	2859
Title:	Apparatus for and Method of Measuring Clock Skew		

July 2, 2003
San Francisco, California

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

Pursuant to the duty of disclosure set forth in 37 CFR § 1.56, Applicants respectfully submit the following information disclosure statement.

The disclosed references are:

US 5,754,437; issued May 19, 1998; Blazo, et al.; filed September 10, 1996.

DE 100 80 443, German Patent Office; published March 22, 2001, with English translation.

DE 100 06 551 German Patent Office; published November 30, 2000.

PCT Application Publication No. WO-99/39216 dated August 5, 1999.

Yamaguchi T. et al: "Extraction of peak-to-peak and RMS sinusoidal jitter using an analytic signal method" VLSI Test Symposium, 2000. Proceedings. 18th IEEE Montreal,, Canada 30 April-4 May 2000, Los Alamitos, CA, USA,IEEE Comput. Soc, US, 30 April 2000 (2000-04-30), pages 395-402.

A sixth reference, US patent 6,400,129 is also being submitted because it is believed to be a counterpart to DE 100 06 551 and may serve as a translation thereof.

Applicants respectfully request that the Examiner initial the cited references shown on the enclosed form PTO-1449 and that the references be made of record in the present application.
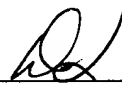
Respectfully submitted,

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Enc. US PTO Form 1449
Cited references (6)
Return receipt postcard

Certificate of Mailing Under 37 CFR 1.8

I certify that this Information Disclosure Statement and all enclosed materials are being deposited with the United States Postal Service on July 2, 2003 with sufficient postage as first class mail in an envelope addressed to Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

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David N. Lathrop

Form PTO-1449		DOCKET KPO112	S.N. 09/813,923
	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	APPLICANT Takahiro Yamaguchi, et al.	
INFORMATION DISCLOSURE STATEMENT		FILING DATE March 20, 2001	GROUP 2859

U.S. PATENT DOCUMENTS

*Exam. Initial		DOCUMENT NUMBER							DATE	NAME	CLASS	SUB- CLASS	FILING DATE
		5	7	5	4	4	3	7	5-19-98	Blazo, et al.			9-10-96
		6	4	0	0	1	2	9	6-4-02	Yamaguchi, et al.			1-28-00

FOREIGN PATENT DOCUMENTS

*Exam. Initial		DOCUMENT NUMBER							DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION YES	NO
	DE	1	00	8	0	4	4	3	3-22-01	German Patent Office			X	
	DE	1	00	0	6	5	5	1	11-30-00	German Patent Office				X
	WO	9	9	3	9	2	1	6	8-5-99	WIPO				

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

		Yamaguchi T. et al: "Extraction of peak-to-peak and RMS sinusoidal jitter using an analytic signal method" VLSI Test Symposium, 2000. Proceedings. 18th IEEE Montreal,, Canada 30 April-4 May 2000, Los Alamitos, CA, USA,IEEE Comput. Soc, US, 30 April 2000 (2000-04-30), pages 395-402.

EXAMINER	DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP; draw line through citation if not in conformance and not considered. Include copy of this form with next communication with applicant.